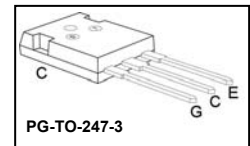
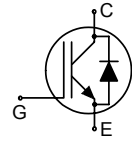


Low Loss DuoPack : IGBT in **TrenchStop®** and Fieldstop technology
with soft, fast recovery anti-parallel EmCon HE diode

- Short circuit withstand time – 10μs
- Designed for :
 - Soft Switching Applications
 - Induction Heating
- **TrenchStop®** and Fieldstop technology for 1200 V applications offers :
 - very tight parameter distribution
 - high ruggedness, temperature stable behavior
 - easy parallel switching capability due to positive temperature coefficient in $V_{CE(sat)}$
- Very soft, fast recovery anti-parallel EmCon™ HE diode
- Low EMI
- Qualified according to JEDEC¹ for target applications
- Application specific optimisation of inverse diode
- •Pb-free lead plating; RoHS compliant



Type	V_{CE}	I_C	$V_{CE(sat)}, T_j=25^\circ\text{C}$	$T_{j,max}$	Marking	Package
IHW40T120	1200V	40A	1.8V	150°C	H40T120	PG-TO247-3

Maximum Ratings

Parameter	Symbol	Value	Unit
Collector-emitter voltage	V_{CE}	1200	V
DC collector current	I_C	75 40	A
$T_C = 25^\circ\text{C}$			
$T_C = 100^\circ\text{C}$			
Pulsed collector current, t_p limited by $T_{j,max}$	$I_{C,puls}$	105	
Turn off safe operating area	-	105	
$V_{CE} \leq 1200\text{V}, T_j \leq 150^\circ\text{C}$			
Diode forward current	I_F	31 19.8	
$T_C = 25^\circ\text{C}$			
$T_C = 100^\circ\text{C}$			
Diode pulsed current, t_p limited by $T_{j,max}$	$I_{F,puls}$	47	
Diode surge non repetitive current, t_p limited by $T_{j,max}$	I_{FSM}	78 200 160	A
$T_C = 25^\circ\text{C}, t_p = 10\text{ms}$, sine halfwave			
$T_C = 25^\circ\text{C}, t_p \leq 2.5\mu\text{s}$, sine halfwave			
$T_C = 100^\circ\text{C}, t_p \leq 2.5\mu\text{s}$, sine halfwave			
Gate-emitter voltage	V_{GE}	± 20	V
Short circuit withstand time ²⁾	t_{SC}	10	μs
$V_{GE} = 15\text{V}, V_{CC} \leq 1200\text{V}, T_j \leq 150^\circ\text{C}$			
Power dissipation, $T_C = 25^\circ\text{C}$	P_{tot}	270	W
Operating junction temperature	T_j	-40...+150	°C
Storage temperature	T_{stg}	-55...+150	

¹ J-STD-020 and JEDEC-022

²⁾ Allowed number of short circuits: <1000; time between short circuits: >1s.



Soft Switching Series

IHW40T120

Soldering temperature, 1.6mm (0.063 in.) from case for 10s	-	260	
--	---	-----	--

Thermal Resistance

Parameter	Symbol	Conditions	Max. Value	Unit
Characteristic				
IGBT thermal resistance, junction – case	R_{thJC}		0.45	K/W
Diode thermal resistance, junction – case	R_{thJCD}		1.1	
Thermal resistance, junction – ambient	R_{thJA}		40	

Electrical Characteristic, at $T_j = 25^\circ\text{C}$, unless otherwise specified

Parameter	Symbol	Conditions	Value			Unit
			min.	Typ.	max.	
Static Characteristic						
Collector-emitter breakdown voltage	$V_{(BR)CES}$	$V_{GE}=0V, I_C=1.5mA$	1200	-	-	V
Collector-emitter saturation voltage	$V_{CE(sat)}$	$V_{GE} = 15V, I_C=40A$				
		$T_j=25^{\circ}C$	-	1.8	2.3	
		$T_j=125^{\circ}C$	-	2.1	-	
		$T_j=150^{\circ}C$	-	2.3	-	
Diode forward voltage	V_F	$V_{GE}=0V, I_F=18A$				
		$T_j=25^{\circ}C$		1.65	2.15	
		$T_j=125^{\circ}C$		1.7		
		$T_j=150^{\circ}C$		1.7		
Gate-emitter threshold voltage	$V_{GE(th)}$	$I_C=1.5mA, V_{CE}=V_{GE}$	5.0	5.8	6.5	
Zero gate voltage collector current	I_{CES}	$V_{CE}=1200V,$ $V_{GE}=0V$				mA
		$T_j=25^{\circ}C$	-	-	0.4	
		$T_j=150^{\circ}C$	-	-	4.0	
Gate-emitter leakage current	I_{GES}	$V_{CE}=0V, V_{GE}=20V$	-	-	600	nA
Transconductance	g_{fs}	$V_{CE}=20V, I_C=40A$	-	21	-	S
Integrated gate resistor	R_{Gint}			6		Ω

Dynamic Characteristic

Input capacitance	C_{iss}	$V_{CE}=25V,$ $V_{GE}=0V,$ $f=1MHz$	-	2500	-	pF
Output capacitance	C_{oss}		-	130	-	
Reverse transfer capacitance	C_{rss}		-	110	-	
Gate charge	Q_{Gate}	$V_{CC}=960V, I_C=40A$ $V_{GE}=15V$	-	203	-	nC
Internal emitter inductance measured 5mm (0.197 in.) from case	L_E		-	13	-	nH
Short circuit collector current ¹⁾	$I_{C(SC)}$	$V_{GE}=15V, t_{SC}\leq 10\mu s$ $V_{CC} = 600V,$ $T_j = 25^\circ\text{C}$	-	210	-	A

¹⁾ Allowed number of short circuits: <1000; time between short circuits: >1s.

Switching Characteristic, Inductive Load, at $T_j=25^\circ\text{C}$

Parameter	Symbol	Conditions	Value			Unit
			min.	typ.	max.	
IGBT Characteristic						
Turn-on delay time	$t_{d(on)}$	$T_j=25^{\circ}\text{C}$, $V_{CC}=600\text{V}$, $I_C=40\text{A}$, $V_{GE}=0/15\text{V}$, $R_G=15\Omega$, $L_{\sigma}^{2)}=180\text{nH}$, $C_{\sigma}^{2)}=39\text{pF}$	-	48	-	ns
Rise time	t_r		-	34	-	
Turn-off delay time	$t_{d(off)}$		-	480	-	
Fall time	t_f		-	70	-	
Turn-on energy	E_{on}	Energy losses include “tail” and diode reverse recovery.	-	3.3	-	mJ
Turn-off energy	E_{off}		-	3.2	-	
Total switching energy	E_{ts}		-	6.5	-	

Anti-Parallel Diode Characteristic

Diode reverse recovery time	t_{rr}	$T_j=25^\circ\text{C}$,	-	195	-	ns
Diode reverse recovery charge	Q_{rr}	$V_R=800\text{V}$, $I_F=18\text{A}$,	-	1880	-	nC
Diode peak reverse recovery current	I_{rrm}	$di_F/dt=800\text{A}/\mu\text{s}$	-	20.2	-	A

Switching Characteristic, Inductive Load, at $T_j=150^\circ\text{C}$

Parameter	Symbol	Conditions	Value			Unit
			min.	typ.	max.	
IGBT Characteristic						
Turn-on delay time	$t_{d(on)}$	$T_j=150^{\circ}\text{C}$ $V_{CC}=600\text{V}, I_C=40\text{A},$ $V_{GE}=0/15\text{V},$ $R_G=15\Omega,$ $L_{\sigma}^{1)}=180\text{nH},$ $C_{\sigma}^{1)}=39\text{pF}$ Energy losses include “tail” and diode reverse recovery.	-	52	-	ns
Rise time	t_r		-	40	-	
Turn-off delay time	$t_{d(off)}$		-	580	-	
Fall time	t_f		-	120	-	
Turn-on energy	E_{on}		-	5.0	-	mJ
Turn-off energy	E_{off}		-	5.4	-	
Total switching energy	E_{ts}		-	10.4	-	

Anti-Parallel Diode Characteristic

Diode reverse recovery time	t_{rr}	$T_j=150^\circ\text{C}$	-	300		ns
Diode reverse recovery charge	Q_{rr}	$V_R=800\text{V}$, $I_F=18\text{A}$,	-	3540		nC
Diode peak reverse recovery current	I_{rrm}	$di_F/dt=800\text{A}/\mu\text{s}$	-	25.3		A

2) Leakage inductance L_{σ} and Stray capacity C_{σ} due to dynamic test circuit in Figure E.

1) Leakage inductance L_{σ} and Stray capacity C_{σ} due to dynamic test circuit in Figure E.

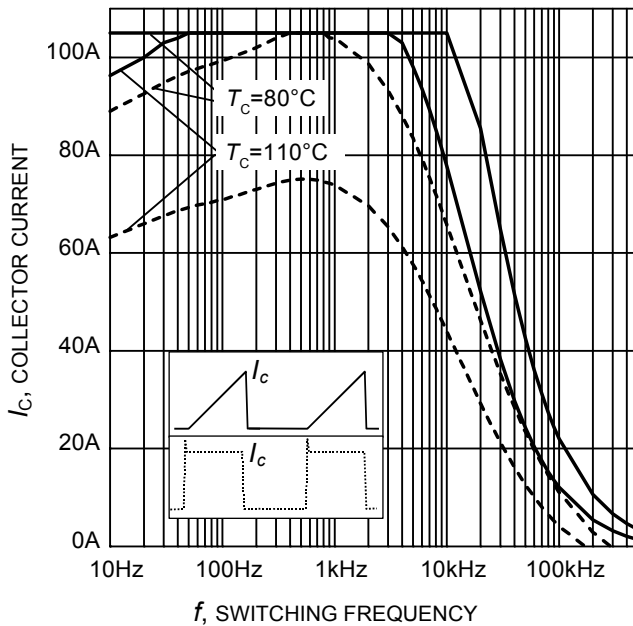


Figure 1. Collector current as a function of switching frequency
 $(T_j \leq 150^\circ\text{C}, D = 0.5, V_{CE} = 600\text{V}, V_{GE} = 0/+15\text{V}, R_G = 15\Omega)$

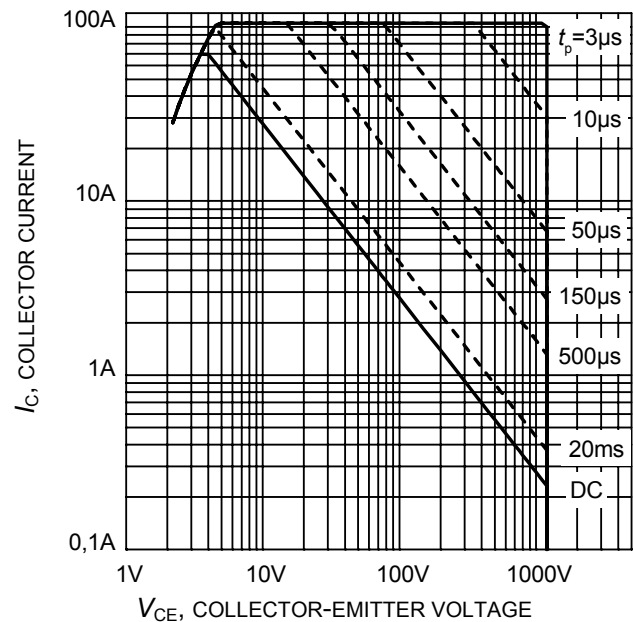


Figure 2. Safe operating area
 $(D = 0, T_C = 25^\circ\text{C}, T_j \leq 150^\circ\text{C}; V_{GE} = 15\text{V})$

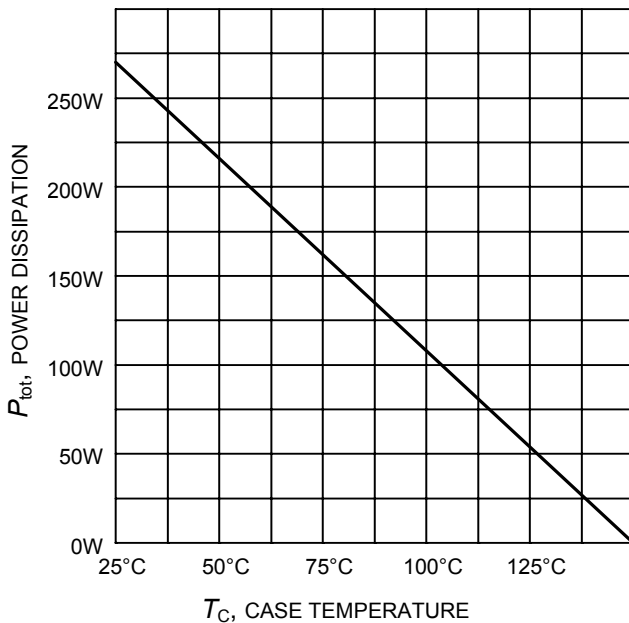


Figure 3. Power dissipation as a function of case temperature
 $(T_j \leq 150^\circ\text{C})$

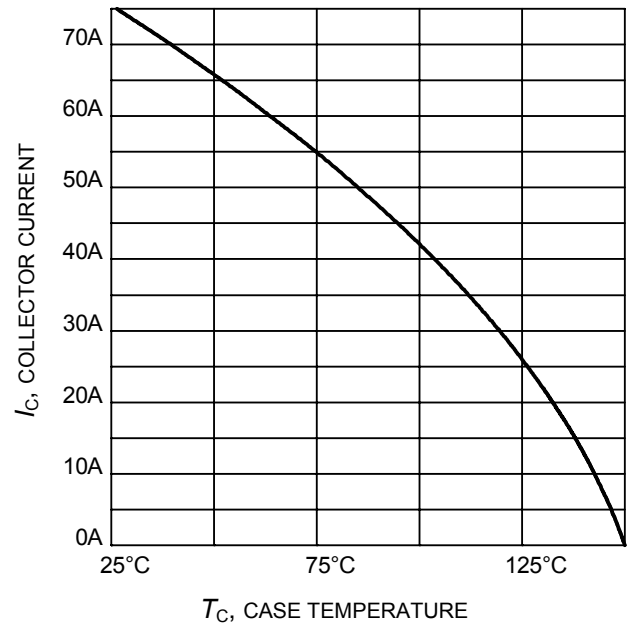


Figure 4. Collector current as a function of case temperature
 $(V_{GE} \geq 15\text{V}, T_j \leq 150^\circ\text{C})$

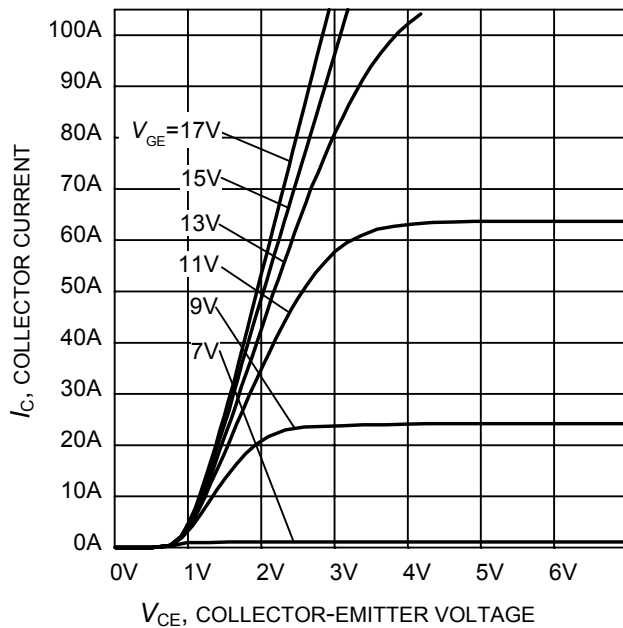


Figure 5. Typical output characteristic
($T_j = 25^\circ\text{C}$)

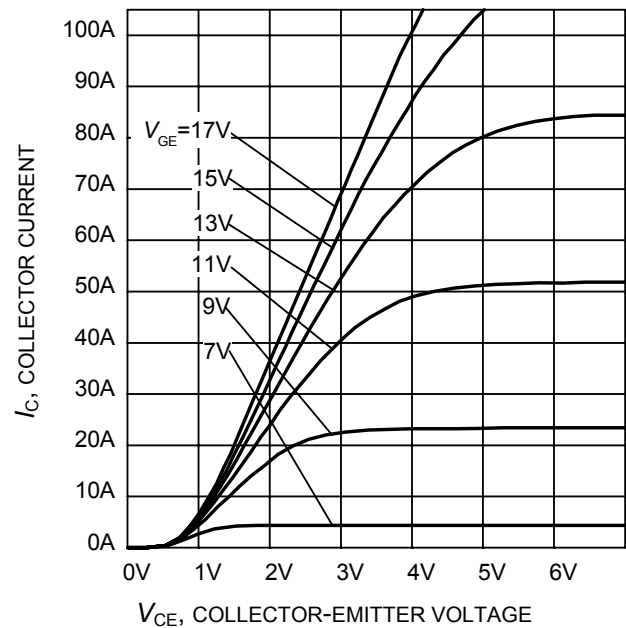


Figure 6. Typical output characteristic
($T_j = 150^\circ\text{C}$)

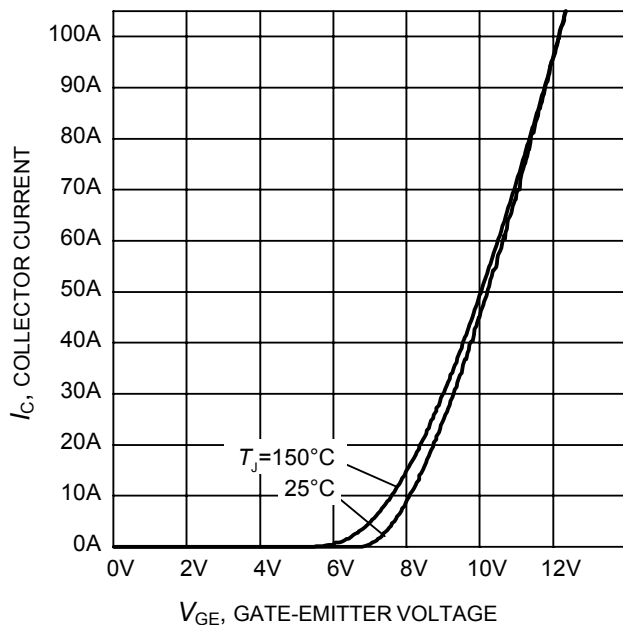


Figure 7. Typical transfer characteristic
($V_{ce} = 20\text{V}$)

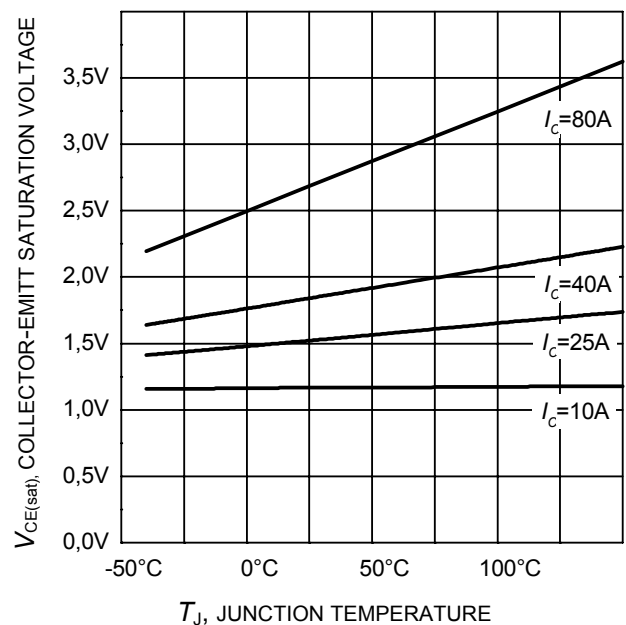


Figure 8. Typical collector-emitter saturation voltage as a function of junction temperature
($V_{ge} = 15\text{V}$)

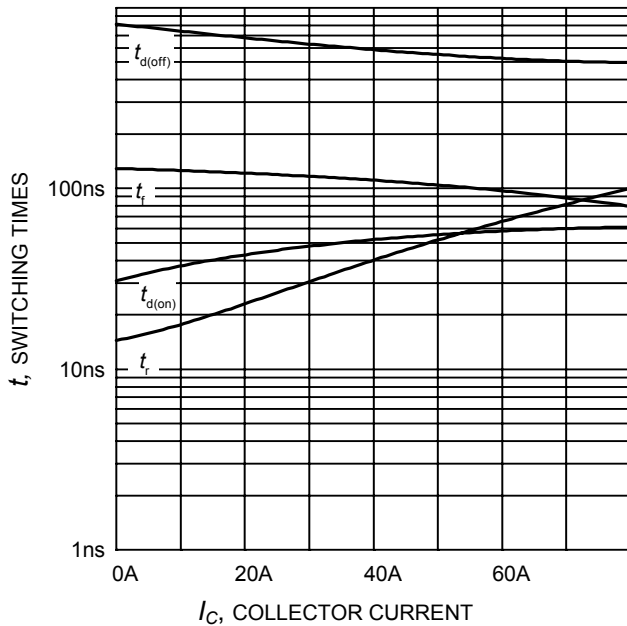


Figure 9. Typical switching times as a function of collector current
(inductive load, $T_J=150^\circ\text{C}$, $V_{CE}=600\text{V}$, $V_{GE}=0/15\text{V}$, $R_G=15\Omega$, Dynamic test circuit in Figure E)

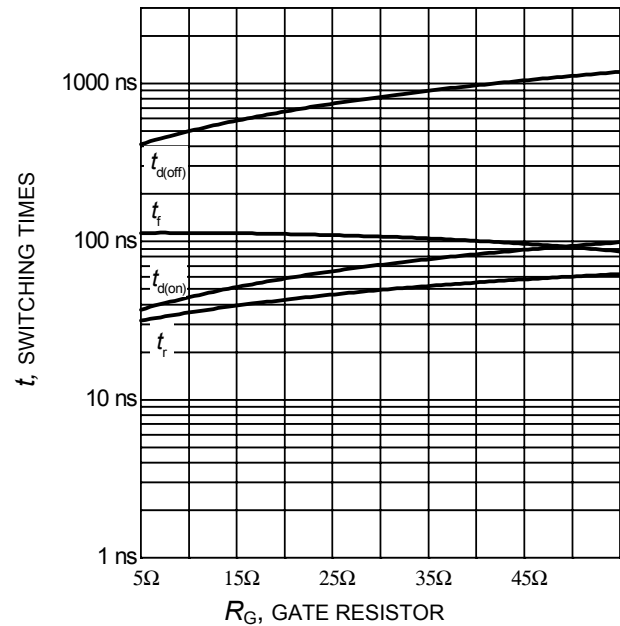


Figure 10. Typical switching times as a function of gate resistor
(inductive load, $T_J=150^\circ\text{C}$, $V_{CE}=600\text{V}$, $V_{GE}=0/15\text{V}$, $I_C=40\text{A}$, Dynamic test circuit in Figure E)

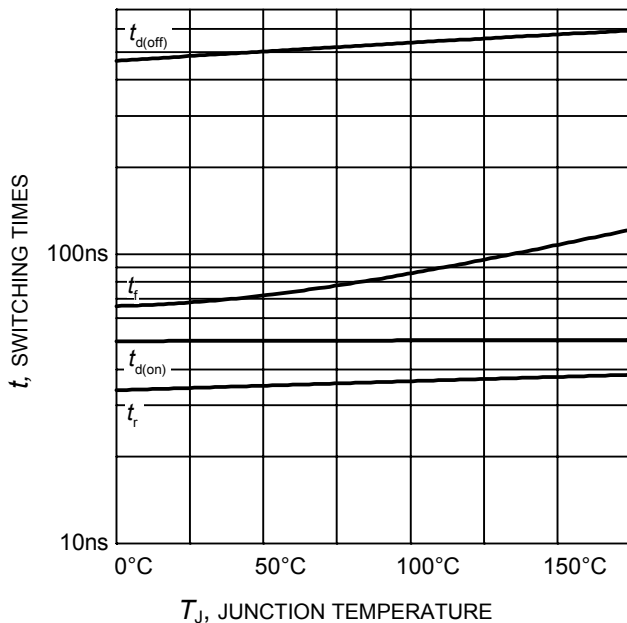


Figure 11. Typical switching times as a function of junction temperature
(inductive load, $V_{CE}=600\text{V}$, $V_{GE}=0/15\text{V}$, $I_C=40\text{A}$, $R_G=15\Omega$, Dynamic test circuit in Figure E)

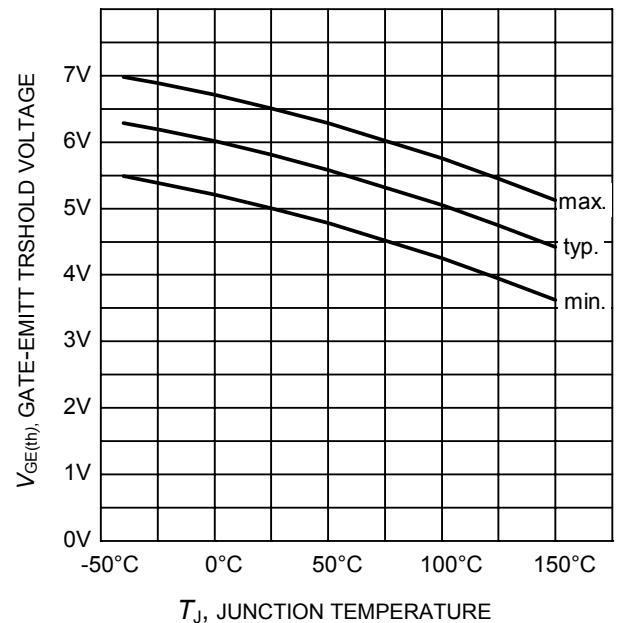


Figure 12. Gate-emitter threshold voltage as a function of junction temperature
($I_C = 1.5\text{mA}$)

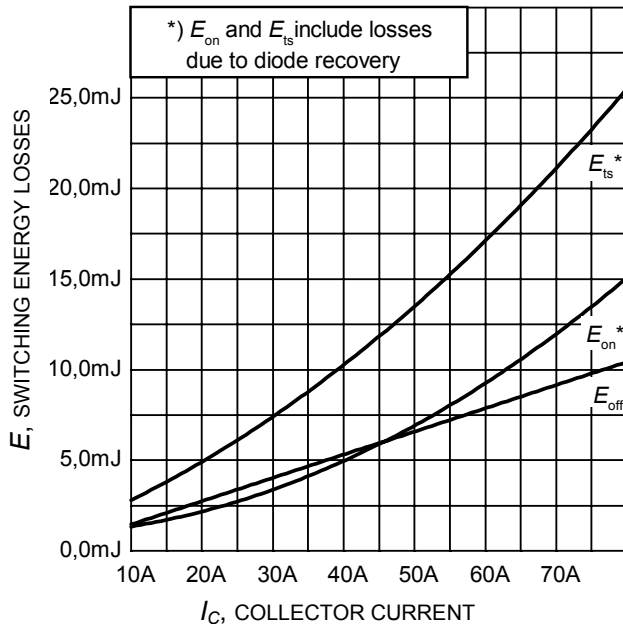


Figure 13. Typical switching energy losses as a function of collector current
(inductive load, $T_J=150^\circ\text{C}$, $V_{CE}=600\text{V}$, $V_{GE}=0/15\text{V}$, $R_G=15\Omega$, Dynamic test circuit in Figure E)

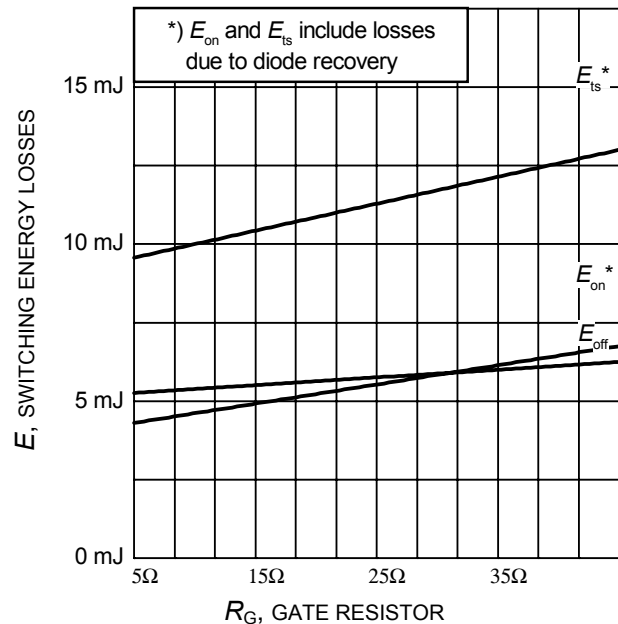


Figure 14. Typical switching energy losses as a function of gate resistor
(inductive load, $T_J=150^\circ\text{C}$, $V_{CE}=600\text{V}$, $V_{GE}=0/15\text{V}$, $I_C=40\text{A}$, Dynamic test circuit in Figure E)

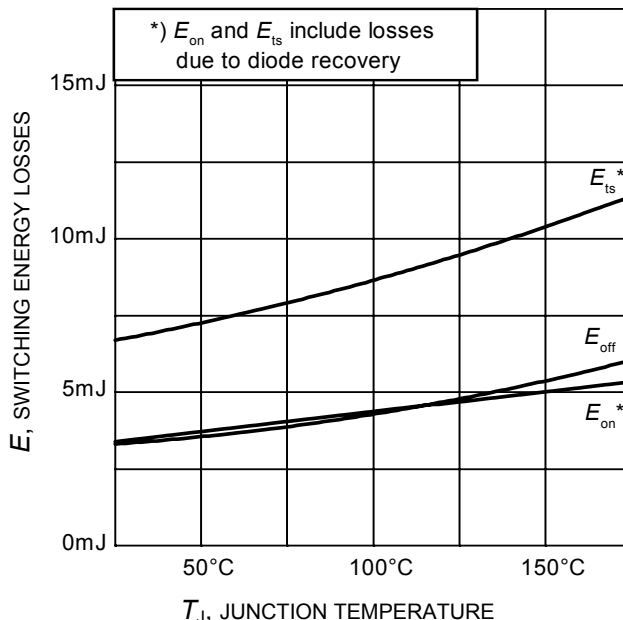


Figure 15. Typical switching energy losses as a function of junction temperature
(inductive load, $V_{CE}=600\text{V}$, $V_{GE}=0/15\text{V}$, $I_C=40\text{A}$, $R_G=15\Omega$, Dynamic test circuit in Figure E)

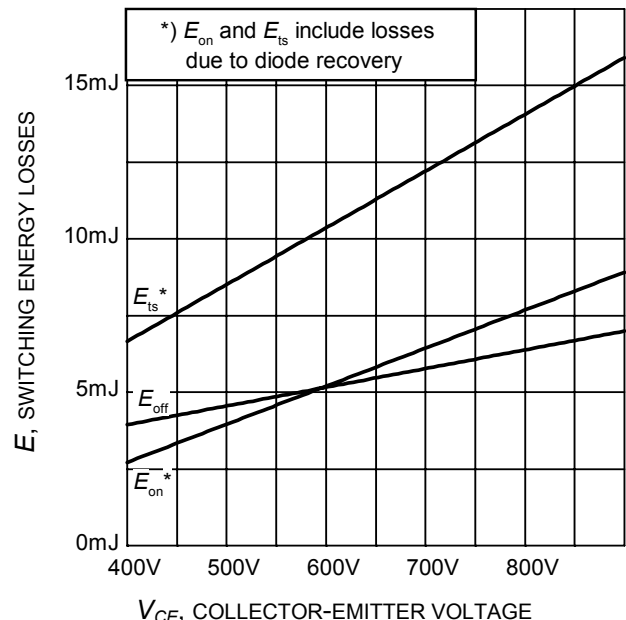


Figure 16. Typical switching energy losses as a function of collector emitter voltage
(inductive load, $T_J=150^\circ\text{C}$, $V_{GE}=0/15\text{V}$, $I_C=40\text{A}$, $R_G=15\Omega$, Dynamic test circuit in Figure E)

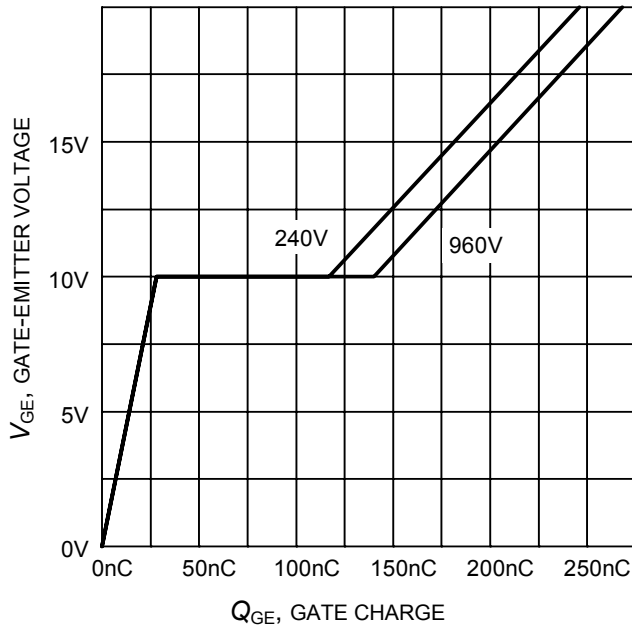


Figure 17. Typical gate charge
($I_C=40\text{ A}$)

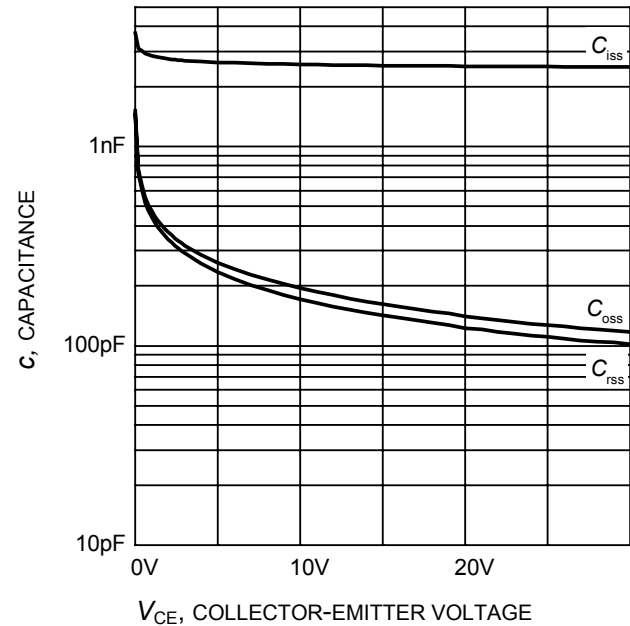


Figure 18. Typical capacitance as a function of collector-emitter voltage
($V_{GE}=0\text{V}$, $f=1\text{ MHz}$)

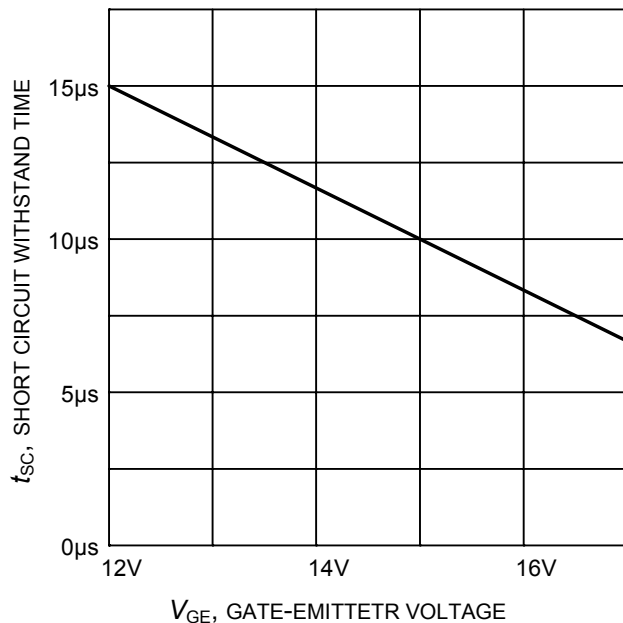


Figure 19. Short circuit withstand time as a function of gate-emitter voltage
($V_{CE}=600\text{V}$, start at $T_J=25^\circ\text{C}$)

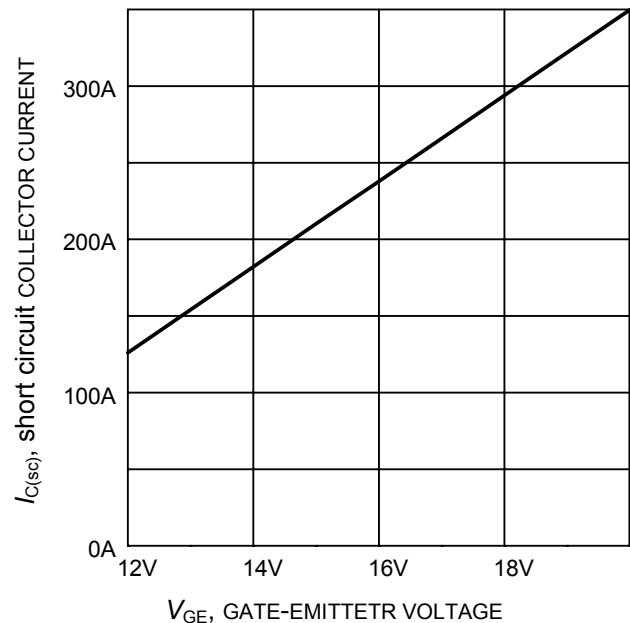


Figure 20. Typical short circuit collector current as a function of gate-emitter voltage
($V_{CE} \leq 600\text{V}$, $T_J \leq 150^\circ\text{C}$)

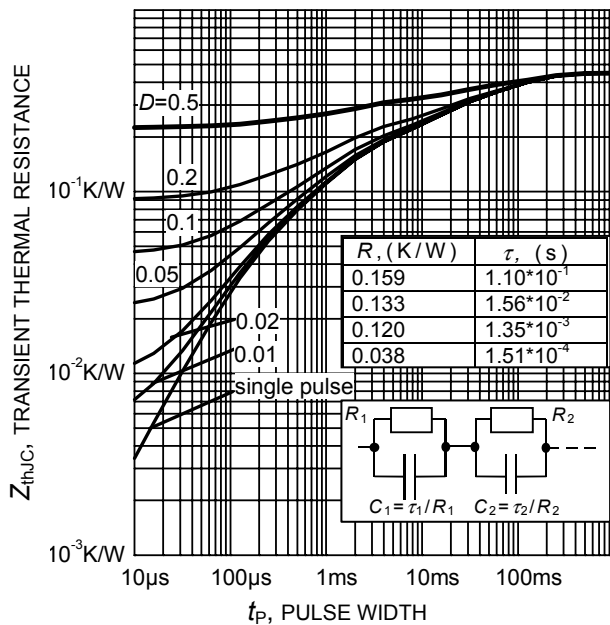


Figure 23. IGBT transient thermal resistance ($D = t_p / T$)

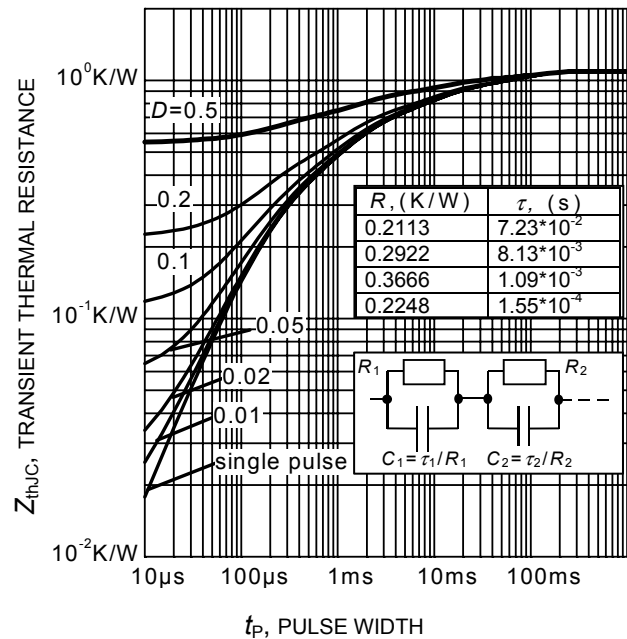


Figure 24. Diode transient thermal impedance as a function of pulse width ($D = t_p / T$)

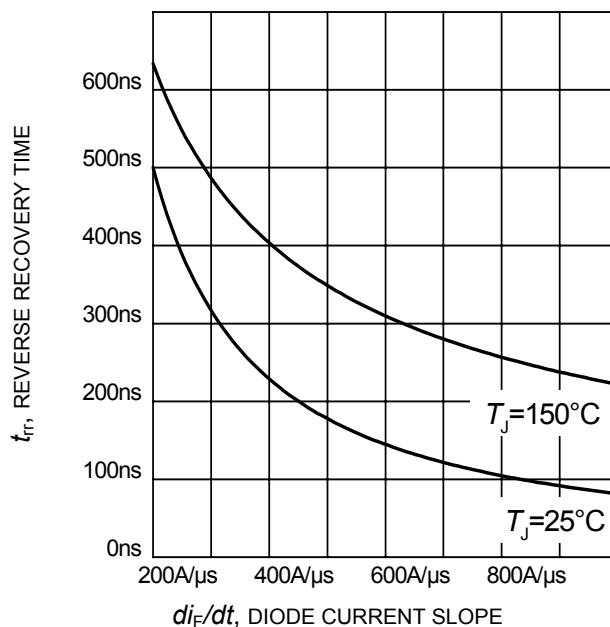


Figure 23. Typical reverse recovery time as a function of diode current slope ($V_R = 600V$, $I_F = 15A$, Dynamic test circuit in Figure E)

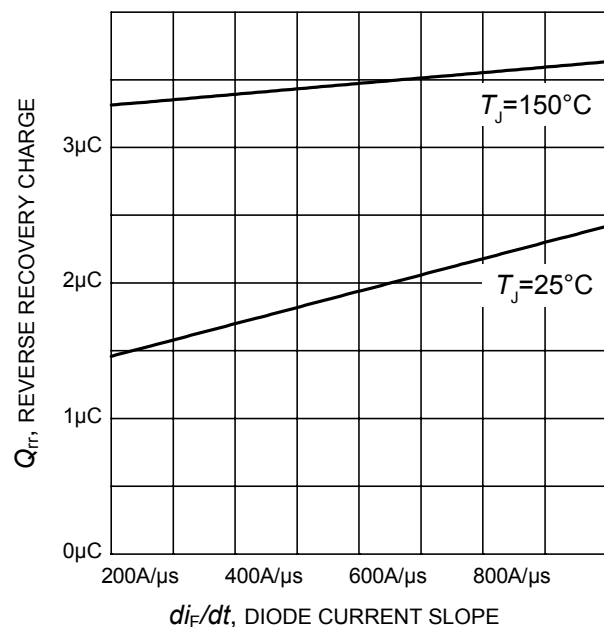


Figure 24. Typical reverse recovery charge as a function of diode current slope ($V_R = 600V$, $I_F = 15A$, Dynamic test circuit in Figure E)

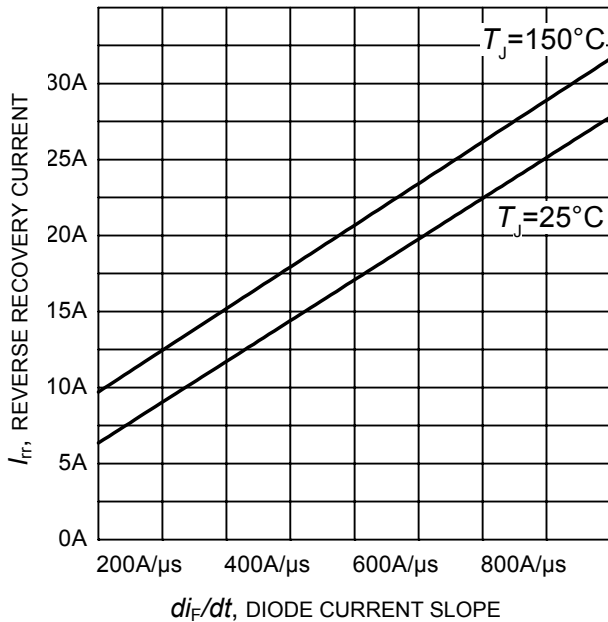


Figure 25. Typical reverse recovery current as a function of diode current slope
($V_R=600V$, $I_F=15A$,
Dynamic test circuit in Figure E)

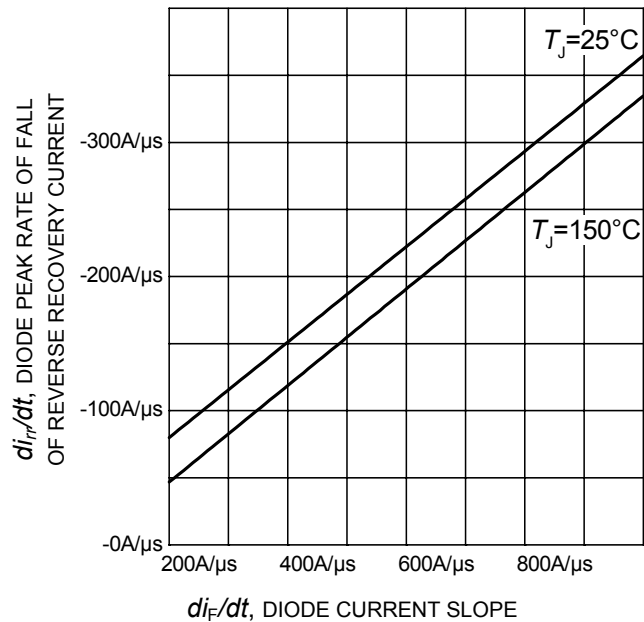


Figure 26. Typical diode peak rate of fall of reverse recovery current as a function of diode current slope
($V_R=600V$, $I_F=15A$,
Dynamic test circuit in Figure E)

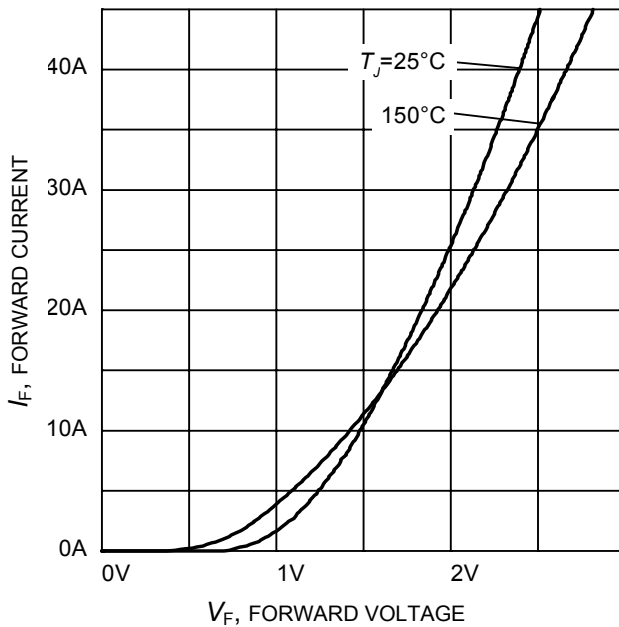


Figure 27. Typical diode forward current as a function of forward voltage

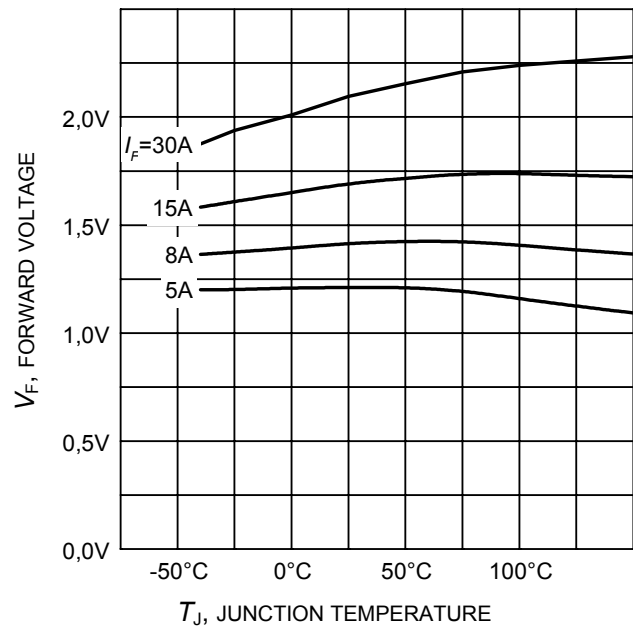
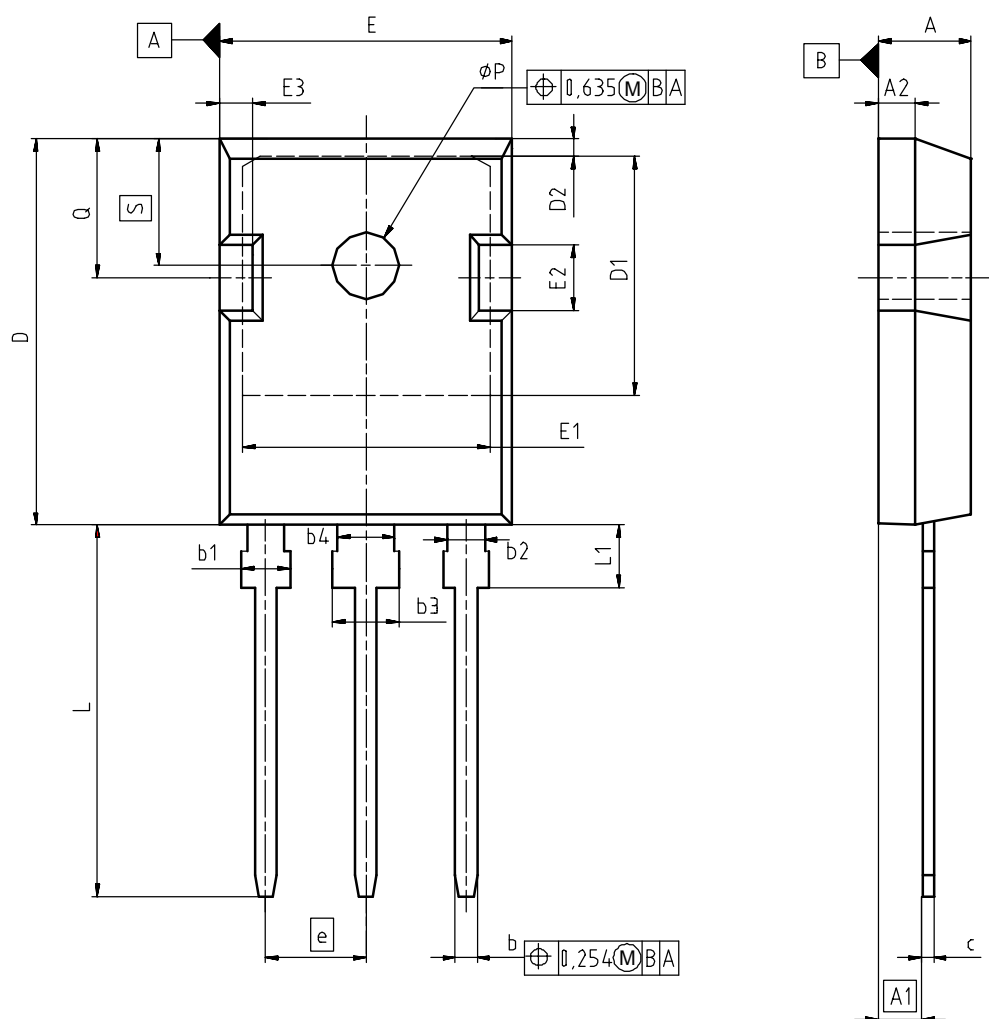
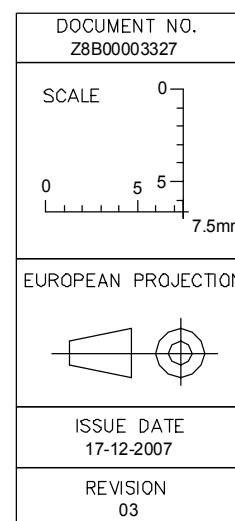


Figure 28. Typical diode forward voltage as a function of junction temperature

PG-TO247-3



DIM	MILLIMETERS		INCHES	
	MIN	MAX	MIN	MAX
A	4.90	5.16	0.193	0.203
A1	2.27	2.53	0.089	0.099
A2	1.85	2.11	0.073	0.083
b	1.07	1.33	0.042	0.052
b1	1.90	2.41	0.075	0.095
b2	1.90	2.16	0.075	0.085
b3	2.87	3.38	0.113	0.133
b4	2.87	3.13	0.113	0.123
c	0.55	0.68	0.022	0.027
D	20.82	21.10	0.820	0.831
D1	16.25	17.65	0.640	0.695
D2	1.05	1.35	0.041	0.053
E	15.70	16.03	0.618	0.631
E1	13.10	14.15	0.516	0.557
E2	3.68	5.10	0.145	0.201
E3	1.68	2.60	0.066	0.102
e	5.44		0.214	
N	3		3	
L	19.80	20.31	0.780	0.799
L1	4.17	4.47	0.164	0.176
ϕP	3.50	3.70	0.138	0.146
Q	5.49	6.00	0.216	0.236
S	6.04	6.30	0.238	0.248



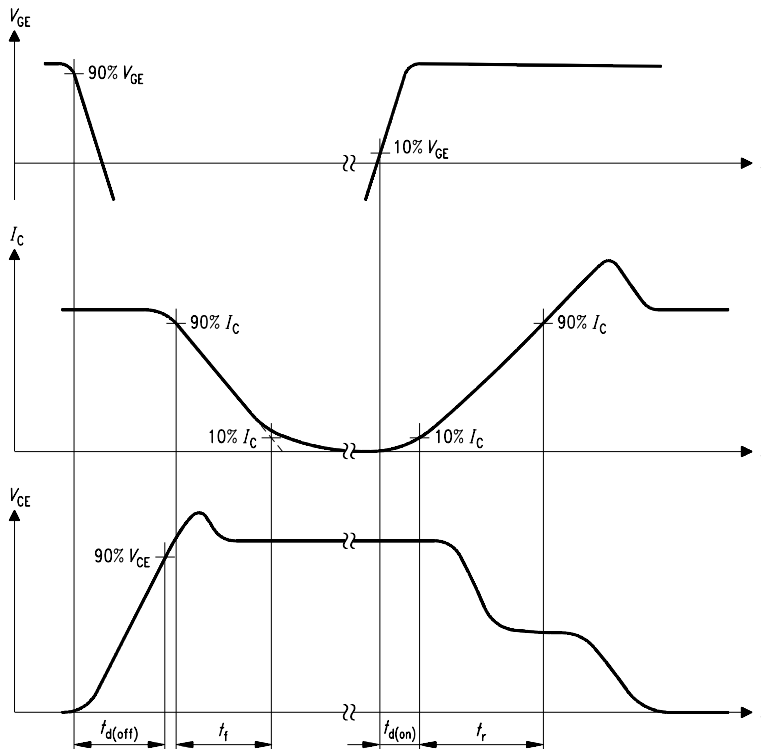


Figure A. Definition of switching times

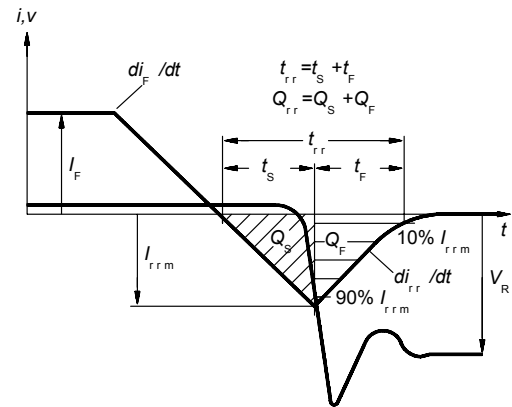


Figure C. Definition of diodes switching characteristics

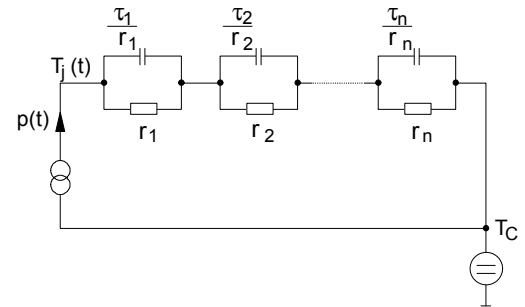


Figure D. Thermal equivalent circuit

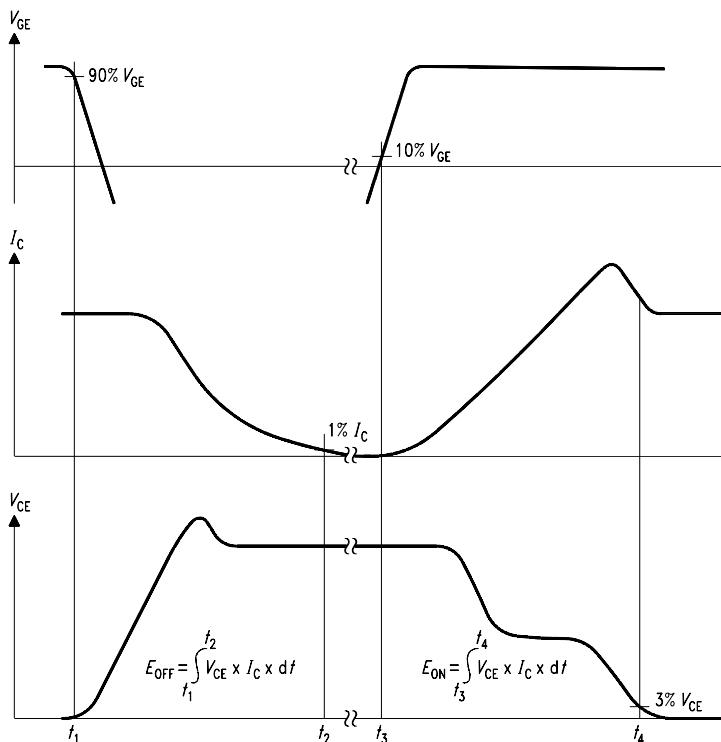
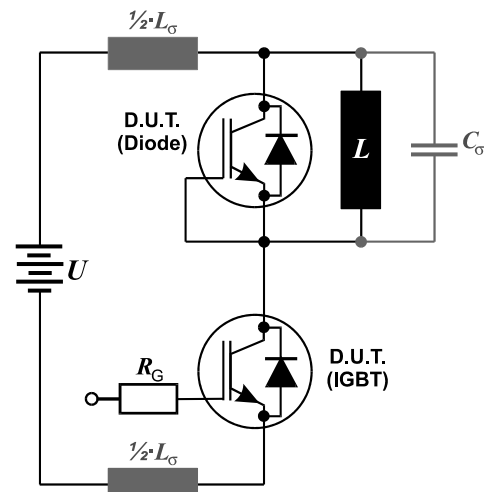


Figure B. Definition of switching losses


Figure E. Dynamic test circuit
Leakage inductance $L_{\sigma} = 180\text{nH}$
and Stray capacity $C_{\sigma} = 39\text{pF}$.

Published by
Infineon Technologies AG
81726 Munich, Germany
© 2008 Infineon Technologies AG
All Rights Reserved.

Legal Disclaimer

The information given in this document shall in no event be regarded as a guarantee of conditions or characteristics. With respect to any examples or hints given herein, any typical values stated herein and/or any information regarding the application of the device, Infineon Technologies hereby disclaims any and all warranties and liabilities of any kind, including without limitation, warranties of non-infringement of intellectual property rights of any third party.

Information

For further information on technology, delivery terms and conditions and prices, please contact the nearest Infineon Technologies Office (www.infineon.com).

Warnings

Due to technical requirements, components may contain dangerous substances. For information on the types in question, please contact the nearest Infineon Technologies Office. Infineon Technologies components may be used in life-support devices or systems only with the express written approval of Infineon Technologies, if a failure of such components can reasonably be expected to cause the failure of that life-support device or system or to affect the safety or effectiveness of that device or system. Life support devices or systems are intended to be implanted in the human body or to support and/or maintain and sustain and/or protect human life. If they fail, it is reasonable to assume that the health of the user or other persons may be endangered.